

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10781354	DICKEN, VOLKER
	<b>Examiner</b>	<b>Art Unit</b>
	Hajnik, Daniel F	2628

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Update search conducted in EAST; NPL search conducted in ACM, Google, and IEEE, search terms include voxel, distance fields, 2D, and projection	8/20/08	DFH
EAST text search (US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB -- see search history printout)	8/20/08	DFH

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

/DANIEL F HAJNIK/  
Examiner.Art Unit 2628